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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Tsuneo ABE

Serial No.: 10/758,527

Group Art Unit: 2857

Filed: January 16, 2004

Examiner: Charioui, M.

For: SEMICONDUCTOR DEVICE HAVING A TEST CIRCUIT FOR TESTING AN
OUTPUT CIRCUIT

Honorable Commissioner of Patents
Alexandria, Virginia 22313-1450

AMENDMENT UNDER 37 C.F.R. §1.111

Sir:

In response to the Office Action dated March 25, 2005, please amend the above-identified application as follows: